g		GE Energy		Functional Testing Specification				
	Renewal Serv Louisville, KY		LOU-GEF-IC609SJR100					
Test Procedure for: IC609SJR100								
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Functional test procedure for: IC609SJR100

## 1. SCOPE

1.1 This is a functional testing procedure for a: Test Procedure.doc

# 2. STANDARDS OF QUALITY

2.1 Refer to the current revision of the IPC-A-610 standard for workmanship standards.

# 3. APPLICABLE DOCUMENTS

3.1 The following document(s) shall form part of this specification to the extent specified herein. Unless otherwise indicated, the latest issue shall apply.
2.1.1

# 4. **ENGINEERING REQUIREMENTS**

- 4.1 Equipment Cleaning
  - **4.1.1** Equipment should be clean and free of debris prior to applying power unless performing an initial check. Refer to the local documented procedures for cleaning guidelines.
- 4.2 Equipment Inspection
  - **4.2.1** Equipment should be visually inspected for any defects prior to applying power. This inspection should include the following as a minimum:
    - 4.2.1.1 Wires broken or cracked
    - 4.2.1.2 Terminal strips / connectors broken or cracked
    - **4.2.1.3** Loose wires
    - 4.2.1.4 Components visually damaged
    - 4.2.1.5 Capacitors leaking
    - 4.2.1.6 Solder joints damaged or cold
    - 4.2.1.7 Circuit board burned or de-laminated
    - 4.2.1.8 Printed wire runs burned or damaged

# 5. EQUIPMENT REQUIRED

**5.1** The following equipment is required to perform the process requirements. Equipment may be substituted provided that all accuracy's and test ratios are equivalent or better.

Qty	Reference #	Description
1		Series One Junior
1		Portable Programmer
1		Series One Junior Test Box (115VAC)
1		Series One I/O Expansion Rack

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# 6. TESTING PROCESS

## 6.1 Setup

- **6.1.1** Replaced RAM and battery.
- **6.1.2** Power up the Series One Junior first to see if it will come on line, 115VAC. If OK continue.
- 6.1.3 Hook up Series One Junior 115VAC Test box to the UUT. Be sure communications cable between the Junior and the expansion rack is connected.
- **6.1.4** Flip top row of test switches to the middle position and the bottom row of switch down on the test box.
- **6.1.5** Turn power on and turn key switch on programmer panel to Program or flip switch to the Program Position.
- **6.1.6** Install the following program into CPU using the portable programmer. Clear memory first then start with the 1<sup>st</sup> Bit.
- **6.1.7** To Clear memory enter

Clear SHF 348 Delete NXT

THIS CLEARS THE MEMORY

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6.1	<b>.8</b> Ex	ercise F	Progran	n								
1st Bit on Junior	NXT STR	STR TMR	SHF SHF	0 600	ENT ENT	TMR OUT	SHF SHF	600 17	ENT ENT	SHF	1	ENT
2nd Bit	STR SHF OUT	SHF <b>15</b> SHF	15 ENT 20	ENT STR ENT	STR CNT	SHF SHF	16 610	ENT ENT	CNT OR	SHF SHF	610 1	ENT ENT
3rd Bit	NXT STR	STR TMR	SHF SHF	2 602	ENT ENT	TMR OUT	SHF SHF	602 21	ENT ENT	SHF	1	ENT
4th Bit	NXT STR	STR TMR	SHF SHF	3 603	ENT ENT	TMR OUT	SHF SHF	603 22	ENT ENT	SHF	1	ENT
5th Bit	NXT STR	STR TMR	SHF SHF	4 604	ENT ENT	TMR OUT	SHF SHF	604 23	ENT ENT	SHF	1	ENT
6th Bit	NXT STR	STR TMR	SHF SHF	5 605	ENT ENT	TMR OUT	SHF SHF	605 24	ENT ENT	SHF	1	ENT
7th Bit	NXT STR	STR TMR	SHF SHF	6 606	ENT ENT	TMR OUT	SHF SHF	606 25	ENT ENT	SHF	1	ENT
8th Bit	NXT STR	STR TMR	SHF SHF	7 607	ENT ENT	TMR OUT	SHF SHF	607 26	ENT ENT	SHF	1	ENT
9th Bit	NXT STR	STR TMR	SHF SHF	10 611	ENT ENT	TMR OUT	SHF SHF	611 27	ENT ENT	SHF	1	ENT
I/O Expansion Rack	ı											
1st Bit	NXT STR	STR TMR	SHF SHF	11 612	ENT ENT	TMR OUT	SHF SHF	612 30	ENT ENT	SHF	2	ENT
2nd Bit	NXT STR	STR TMR	SHF SHF	12 613	ENT ENT	TMR OUT	SHF SHF	613 31	ENT ENT	SHF	2	ENT
3rd Bit	NXT STR	STR TMR	SHF SHF	13 614	ENT ENT	TMR OUT	SHF SHF	614 32	ENT ENT	SHF	2	ENT
4th Bit	NXT STR	STR TMR	SHF SHF	14 615	ENT ENT	TMR OUT	SHF SHF	615 33	ENT ENT	SHF	2	ENT

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### 6.2 <u>Testing Procedure</u>

- **6.2.1** Once done you should see an End of Program statement.
- **6.2.2** Turn or flip switch to RUN.
- **6.2.3** Flip switch 0 down and approximately 1-second later light 0 should come on.
- **6.2.4** Flip switch 1 down and immediately light 1 should come on.
- **6.2.5** Flip switch 2 down and approximately 1-second later light 2 should come on.
- **6.2.6** The panel should stay the same through switch 7.
- **6.2.7** Flip switch 10 up and approximately 1-second later light 10 should come on.
- **6.2.8** Flip switch 11 up and approximately 2 seconds later light 0 on the output card in the expansion rack should come on.
- **6.2.9** Flip switch 12 up and approximately 2 seconds later light 1 on the output card in the expansion rack should come on.
- **6.2.10** Flip switch 13 up and approximately 2 seconds later light 2 on the output card in the expansion rack should come on.
- **6.2.11** Flip switch 14 up and approximately 2 seconds later light 3 on the output card in the expansion rack should come on.
- **6.2.12** Flip all switches to their original position, off.
- **6.2.13** Push black button 15 times, Lamp 1 should come. Reset lamp by pressing red button, repeat once.
- **6.2.14** End of Test
- 6.3 \*\*\*TEST COMPLETE \*\*\*
- 7. <u>NOTES:</u>

8.